

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination NAKANO ET AL.	
		Examiner Chuc D. Tran	Art Unit 2821	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2003/0156744	08-2003	Hashimoto, Seiji	382/124
	B	US-2004/0234110	11-2004	Chou, Bruce C. S.	382/122
	C	US-6,914,517	07-2005	Kinsella, David J.	340/5.83
	D	US-2003/0123714	07-2003	O'Gorman et al.	382/124
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP2004171307	11-2002	Japan	Funabashi Takeshi	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.